GN009 Application Note

PCB Layout Considerations with GaN E-HEMTs

March 08, 2022

GaN Systems Inc.

- This guide provides an overview of the good engineering practice for PCB layout of designs using GaN Systems' E-HEMTs.

- Layout guidelines are introduced for the following four circuit configurations

  1) Isolated gate driver circuit for single GaN E-HEMTs

  2) Isolated gate driver circuit for paralleled GaN E-HEMTs

  3) Half-bridge Booststrap gate driver circuit

  4) EZDrive^{SM} circuit

- With optimum board layout combined with low package inductance, GaN E-HEMTs exhibit optimum switching performance
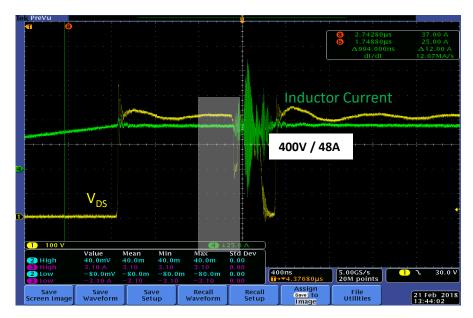
- GaN Systems' E-HEMTs have very low packaging inductance, while enabling ultra-low inductance PCB power loops.

- Good engineering practice of layout techniques are required to minimize parasitic inductance and fully utilize the benefit of GaN Systems' E-HEMTs.

- This application note shows key steps to design an optimal PCB layout with GaN to maximize converter performance.
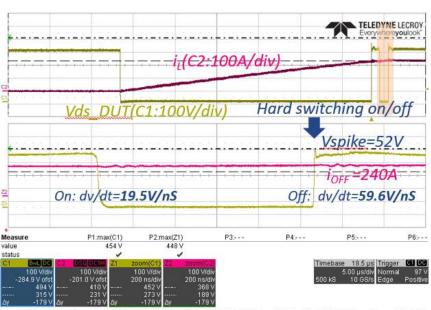
- GaN E-HEMTs switch much faster than Si MOSFETs, and require proper engineering consideration of PCB layout design to minimize parasitic inductances.

- Parasitic inductances can cause higher overshoot voltages, ringing/oscillation, EMC issues, which can lead to overstressing the E-HEMTs.

Example of an unsuccessful design caused by unbalanced quasi-common source inductance

Example of clean switching waveforms when good PCB layout practices are used (400 V/240 A DPT)

Step 1: Prepare the schematics and identify the components of each critical loop

- Isolated gate driver circuit for single GaN HEMTs
- Isolated gate driver circuit for paralleled GaN HEMTs
- Half-bridge Bootstrap gate driver circuit
- EZDrive^{SM} circuit

Step 2: Place the components according to the design priority and current direction

- Put components as close as possible
- According to the current direction, set the component in sequence
- If there is a conflict for minimizing all the loops, refer to the priority listed on slide 7/8/9/10.

Step 3: Connect the components optimally to achieve low parasitics with flux cancellation techniques

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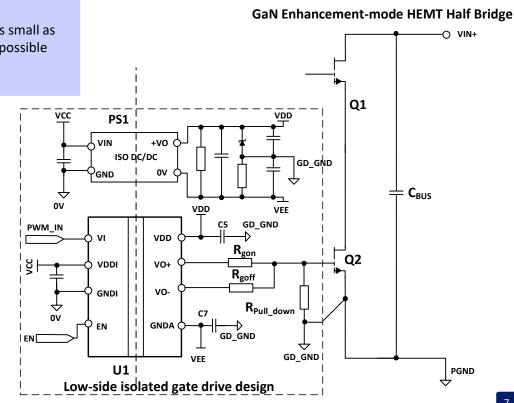- If there is a conflict for minimizing all the loops, refer to the priority listed on slide 7/8/9/10.

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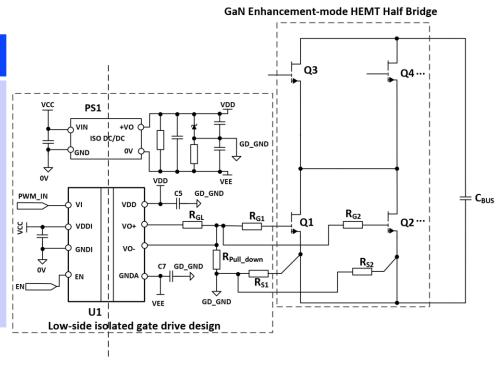
Isolated gate driver circuit for single GaN HEMT

Priority	Critical Loops	Components	Critical Loops Design Rule
1	Power Commutation loop	$Q1, Q2, C_{BUS}$	
2a	LS Gate Driver loop (turn-on)	$C5, U1, R_{gon}, Q2$	As small as possible
2b	LS Gate Driver loop (turn-off)	$C7, U1, R_{goff}, Q2$	

- High-side isolated gate drive design is symmetric as Low-side, not shown in the diagram

- Priority of HS gate driver loop is same as LS

GaN Enhancement-mode HEMT Half Bridge

Isolated gate driver circuit for paralleled GaN HEMTs
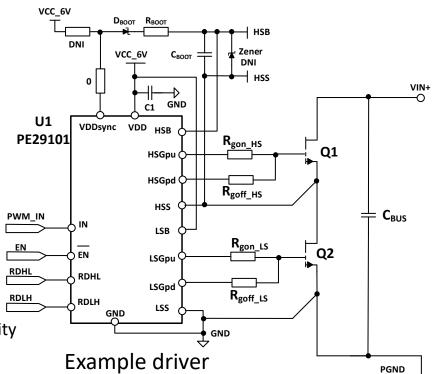
Priority	Critical Loops	Components	Critical Loops Design Rule
1a	Quasi-common source loop (high-side)	Q3, Q4	As small and symmetric for each of paralleled devices as possible
1b	Quasi-common source loop (low-side)	Q1, Q2	
2	Power Commutation loop	C_{BUS}, Q3/Q4, Q1/Q2	
3a	LS Gate Driver loop (turn-on)	C5, U1, RGL, R_{G1}/Q1/R_{S1}, R_{G2}/Q2/R_{S2}	
3b	LS Gate Driver loop (turn-off)	C7, U1, R_{G1}/Q1/R_{S1}, R_{G2}/Q2/R_{S2}	

GaN Enhancement-mode HEMT Half Bridge

Low-side isolated gate drive design

- High-side isolated gate drive design is symmetric as Low-side, not shown in the diagram
- Priority of HS gate driver loop is same as LS
- **Distributed gate and source resistance R_{G1}/ R_{G2} and R_{S1}/ R_{S2} needs to be separated**

Half-bridge Bootstrap Gate Driver Circuit (Non-isolated)

Priority	Critical Loops	Components	Critical Loops Design Rule
1	Power Commutation loop	Q1, Q2, C_{BUS}	
2a	HS Gate Driver Loop (turn-on)	D_{BOOT}, R_{BOOT}, C_{BOOT}, U1, R_{gon_HS}, Q1	
2b	HS Gate Driver Loop (turn-off)	Q1, R_{goff_HS}, U1	As small as possible
2c	LS Gate Driver Loop (turn-on)	C1, U1, R_{gon_LS}, Q2	
2d	LS Gate Driver Loop (turn-off)	Q2, R_{goff_LS}, U1	
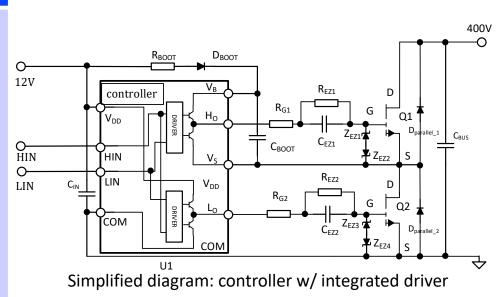
- Use above table to identify critical loop, components and priority

Example driver

EZDrive^{SM} circuit (Non-isolated half-bridge)

Priority	Critical Loops	Components	Critical Loops Design Rule
1	Power Commutation Loop	Q1, Q2, C_{BUS}	As small as possible
2a	HS Gate Driver Loop (turn-on)	R_{BOOT}, D_{BOOT}, C_{BOOT}, U1, R_{G1}, R_{EZ1}, C_{EZ1}, Z_{EZ1}, Z_{EZ2}, Q1	
2b	HS Gate Driver Loop (turn-off)	Q1, Z_{EZ1}, Z_{EZ2}, R_{EZ1}, C_{EZ1}, R_{G1}, U1	
2c	LS Gate Driver Loop (turn-on)	U1, R_{G2}, R_{EZ2}, C_{EZ2}, Z_{EZ3}, Z_{EZ4}, Q2	
2d	LS Gate Driver Loop (turn-off)	Q2, Z_{EZ3}, Z_{EZ4}, R_{EZ2}, C_{EZ2}, R_{G2}, U1	

Simplified diagram: controller w/ integrated driver

- Use above table to identify critical loop, components and priority

Note: more details about EZDrive^{SM} please refer to Application note GN010 at https://gansystems.com/

Step 1: Prepare the schematics and identify the components of each critical loop
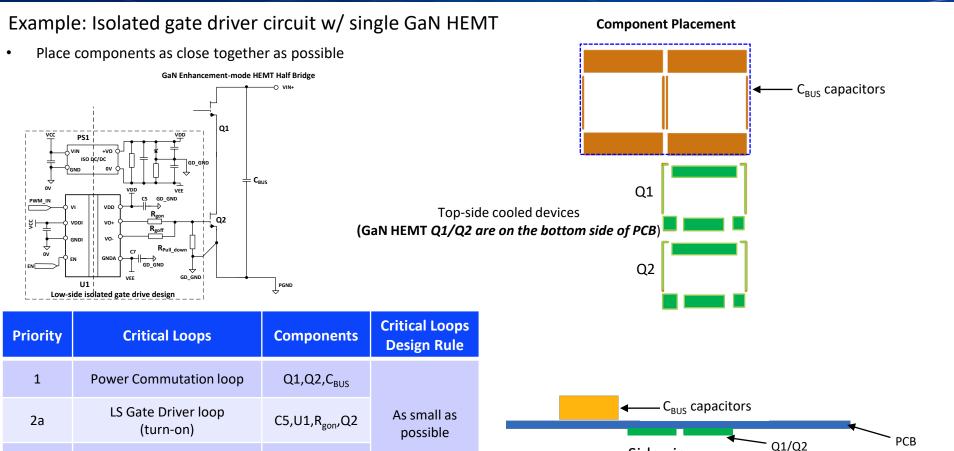
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- Half-bridge Bootstrap gate driver circuit
- EZDrive^{SM} circuit

Step 2: Place the components according to the design priority and current direction

- Put components as close as possible
- According to the current direction, set the component in sequence
- If there is a conflict for minimizing all the loops, refer to the priority listed on slide 7/8/9/10.

Step 3: Connect the components optimally to achieve low parasitics with flux cancellation techniques

Example: Isolated gate driver circuit w/ single GaN HEMT

- Place components as close together as possible

Component Placement

GaN Enhancement-mode HEMT Half Bridge

C_{BUS} capacitors

Q1

Top-side cooled devices
(GaN HEMT *Q1/Q2 are on the bottom side of PCB*)

Q2

Priority	Critical Loops	Components	Critical Loops Design Rule
1	Power Commutation loop	Q1,Q2,C_{BUS}	As small as possible
2a	LS Gate Driver loop (turn-on)	C5,U1,R_{gon},Q2	
2b	LS Gate Driver loop (turn-off)	C7,U1,R_{goff},Q2	

C_{BUS} capacitors

Side view

Q1/Q2

PCB

Step 2.2: Gate Driver Circuit Loop (Top-side cooling)

Example: Isolated gate driver circuit w/ single GaN HEMT

- Locate drivers close to the gate
- Use/create kelvin source for driver return

GaN Enhancement-mode HEMT Half Bridge

Low-side isolated gate drive design

Component Placement

C_{BUS} capacitors

Top-side cooled devices
(GaN HEMT *Q1/Q2* are on the bottom side of PCB)

Priority	Critical Loops	Components	Critical Loops Design Rule
1	Power Commutation loop	Q1,Q2,C_{BUS}	
2a	LS Gate Driver loop (turn-on)	C5,U1,R_{gon},Q2	As small as possible
2b	LS Gate Driver loop (turn-off)	C7,U1,R_{goff},Q2	

C_{BUS} capacitors   Gate driver

Side view   Q1/Q2   PCB

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Example: Isolated gate driver circuit w/ single GaN HEMT

- Place components as close together as possible

GaN Enhancement-mode HEMT Half Bridge

Low-side isolated gate drive design

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2a	LS Gate Driver loop (turn-on)	C5,U1,R_{gon},Q2	As small as possible
2b	LS Gate Driver loop (turn-off)	C7,U1,R_{goff},Q2	

Component Placement

C_{BUS} capacitors

Bottom-side cooled devices
GaN HEMT Q1Q2/caps on the same side of PCB

C_{BUS} capacitors

Q1/Q2

PCB

Side view

Example: Isolated gate driver circuit with single GaN HEMT

- Locate drivers close to the gate
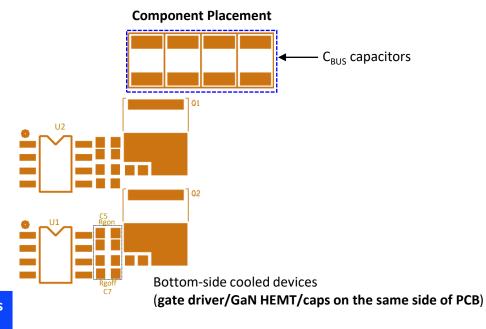
- Use/create kelvin source for driver return

GaN Enhancement-mode HEMT Half Bridge
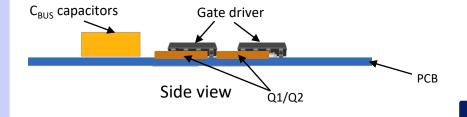

Low-side isolated gate drive design

Component Placement

C_{BUS} capacitors

Bottom-side cooled devices
(gate driver/GaN HEMT/caps on the same side of PCB)

C_{BUS} capacitors — Gate driver

Side view — Q1/Q2 — PCB

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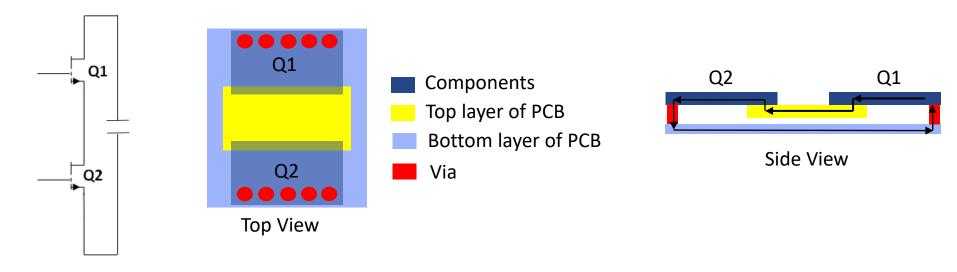- EZDrive^{SM} circuit

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Step 3: Connect the components optimally to achieve low parasitics with flux cancellation techniques

- When two adjacent conductors are located close with opposite current direction, magnetic flux generated by two current flows will cancel each other.

- This magnetic flux canceling effect can lower the parasitic inductance.

- Arrange the layout so that high-frequency current flows in opposite direction on two adjacent PCB layers.
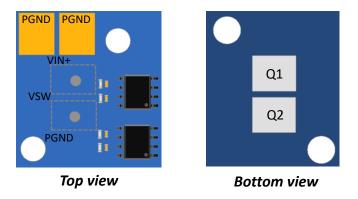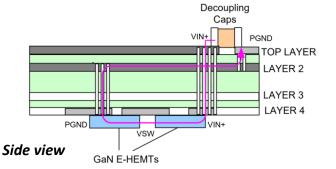
Top View

Components
Top layer of PCB
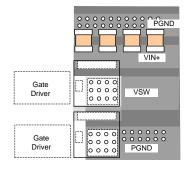Bottom layer of PCB
Via

Side View

- Connect the components with Flux-cancelling traces, see below example of top-side cooled devices and bottom-side cooled devices.

Example: Top-side cooled devices
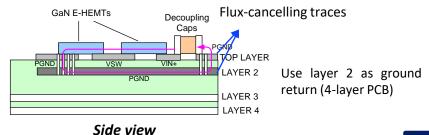**(*GaN HEMT is on the bottom side of PCB*)**

Example: Bottom-side cooled devices
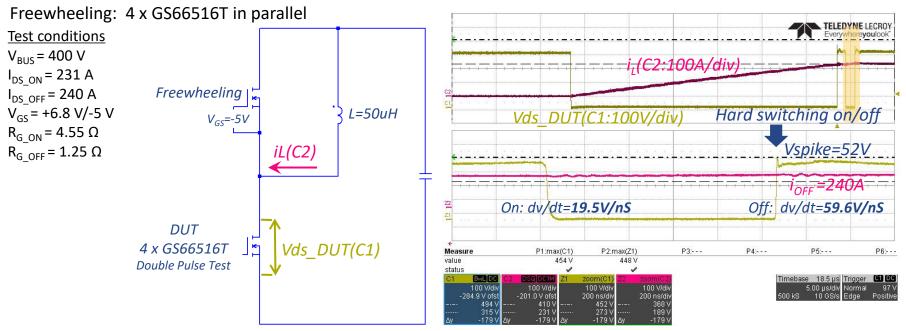**(*gate driver/GaN HEMT/caps on the same side of PCB*)**

Top view

Bottom view

Top view

Side view

Side view

Use layer 2 as ground return (4-layer PCB)

DUT: 4 x GS66516T in parallel.
Freewheeling: 4 x GS66516T in parallel

Test conditions
V_{BUS} = 400 V
I_{DS_ON} = 231 A
I_{DS_OFF} = 240 A
V_{GS} = +6.8 V/-5 V
R_{G_ON} = 4.55 Ω
R_{G_OFF} = 1.25 Ω

Freewheeling

V_{GS}=-5V

L=50uH

iL(C2)

DUT
4 x GS66516T
Double Pulse Test

Vds_DUT(C1)

i_L(C2:100A/div)

Vds_DUT(C1:100V/div)

Hard switching on/off

Vspike=52V

i_{OFF} =240A

On: dv/dt=**19.5V/nS**   Off: dv/dt=**59.6V/nS**

Measurement Setup: Lecroy WaveSurfer 10M Oscilloscope, HVD3106 Differential Probe(C1), CWT-3LFB mini Rogowski Coil(C2)

- Using good engineering practice for PCB layout in designs where GaN Systems' E-HEMTs are paralleled, current balancing and clean switching can be achieved. Hard switched is possible to full rated current.
- This example demonstrates ~200V V_{DS} margin on a 400V/240A hard-switching test

Summary

- Due to faster switching speed of GaN E-HEMTs, good engineering practice for PCB layout techniques are required to minimize parasitic inductance and fully utilize these advanced devices.

- Optimizing the PCB layout is important to achieve the maximum performance capability of GaN based designs. With optimum board layout combined with low GaN*PX*® package inductance, GaN Systems' E-HEMTs exhibit peak switching performance.

Product and application support at

gansystems.com